

Quantitative Microscopy

- Segment Domains
 - Identify similar regions (similar how?)
 - Distinguish from dissimilar regions (dissimilar how?)
- Characteristic of Domains
 - chemistry, crystal type, orientation
- Measurements
 - phase fractions, particle/grain sizes, aspect ratios, spacings, ...



FSD Imaging







set of 3 images → measurements (here 3 intensities) at series of points on specimen

TiVZrHfTa - High Entropy Alloy John C Waite – Oxford Micromechanics Group









Principal Component Analysis

- PCA is a statistical procedure that converts a set of observations (eg several signals measured at a point on specimen) of a number of variables (eg intensity on a FSD diode) into a set of values of linearly uncorrelated (latent) variables called principal components.
- The first principal component (ie linear combination of the measured variables) is constructed so that it gives the largest possible variance across the observations (ie the spatial map has maximum signal variation).
- Succeeding components must be orthogonal to all preceding components and again have the highest variance possible.
- The principal components form an uncorrelated orthogonal basis set.
- PCA can be used to reduce the dimensionality of a problem by retaining only a subset of the most significant PCs (ie useful for data reduction).

$$Var(X) = \frac{1}{n} \sum_{i=1}^{n} (x_i - \mu)^2$$

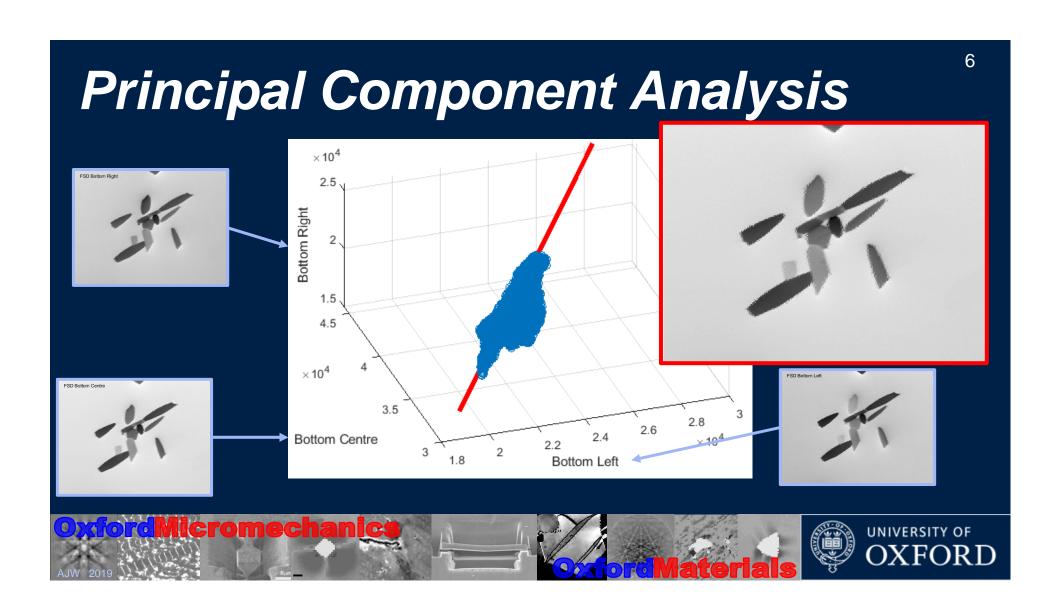
$$\mu(X) = \frac{1}{n} \sum_{i=1}^{n} x_i$$

$$Covar(X,Y) = \frac{1}{n} \sum_{i=1}^{n} (x_i - \mu(X)) (y_i - \mu(Y))$$

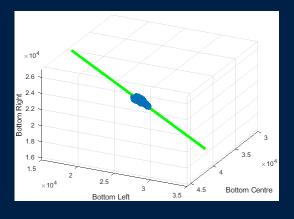


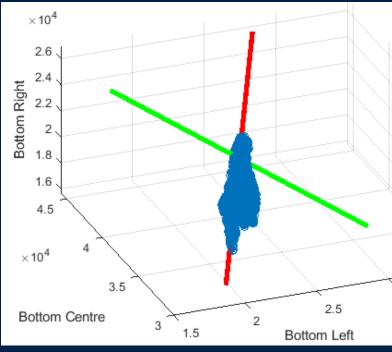




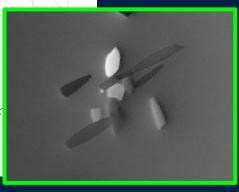


Principal Component Analysis





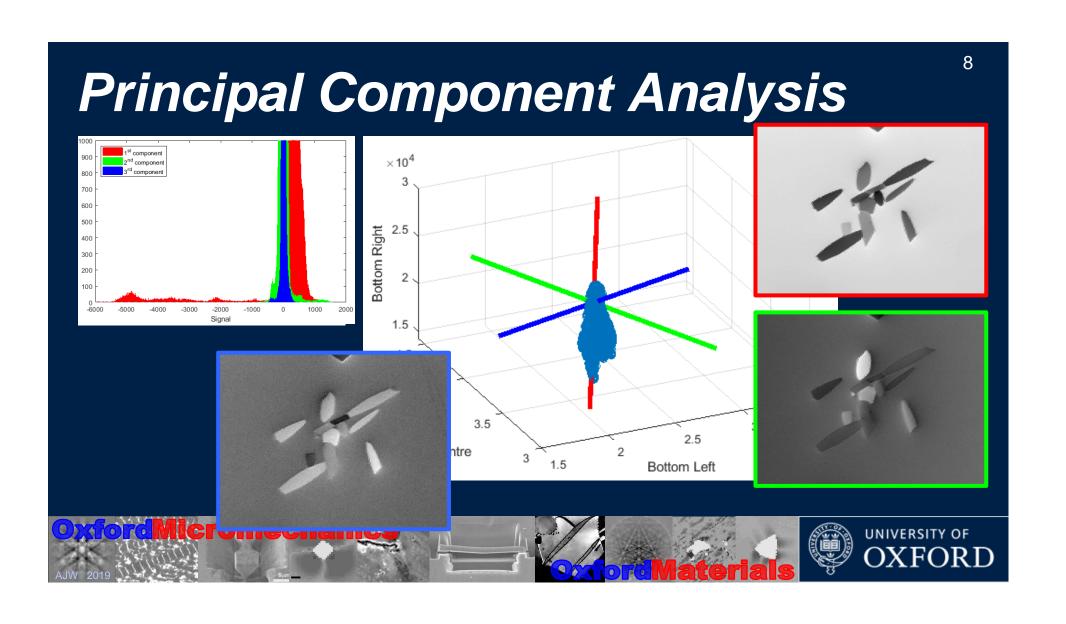




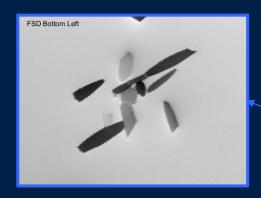
Oxford Micromechanics



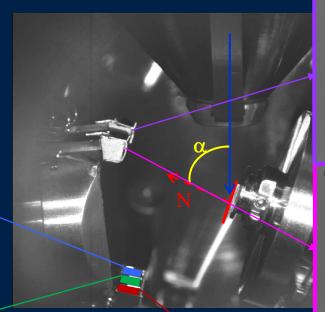


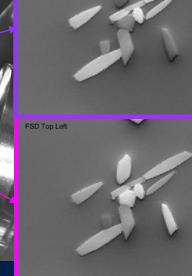


FSD Imaging









FSD Bottom Right

FSD Top Right

More than 3 input variables?
Same idea but can't easily plot/visualise the

Same idea but can't easily plot/visualise the process – 5D plots needed









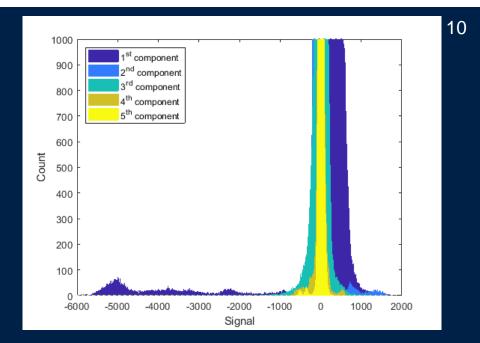
FSD Imaging

Using 5 FSD signals

Same idea but can't easily plot/visualise the process – 5D scatter plots needed

Note little new information added by last few components

The EBSD detector measures intensities at many pixels → extend process further...













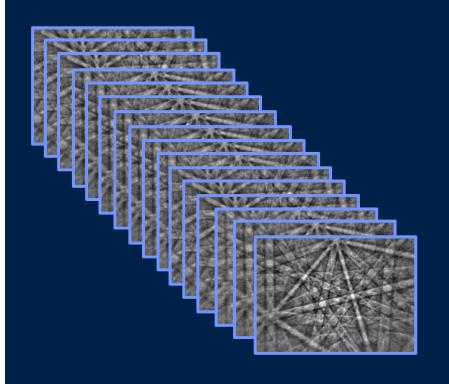


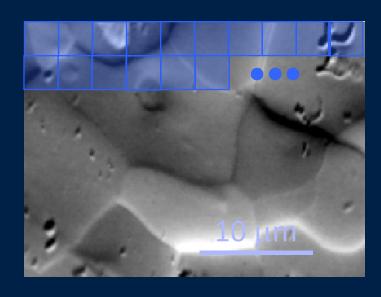






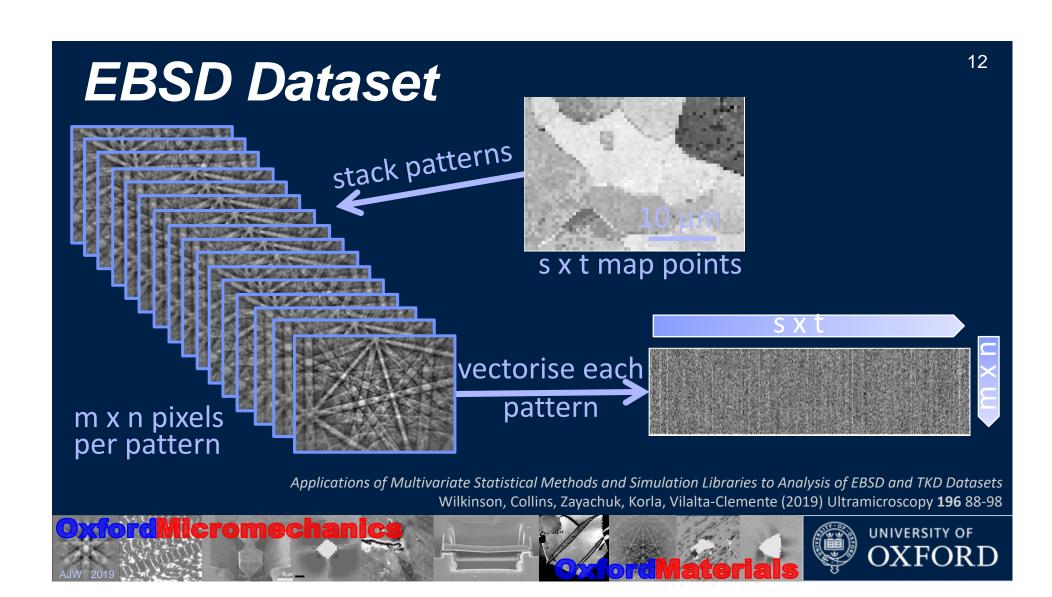
EBSD Dataset





Ferritic Steel Sample – David M Collins

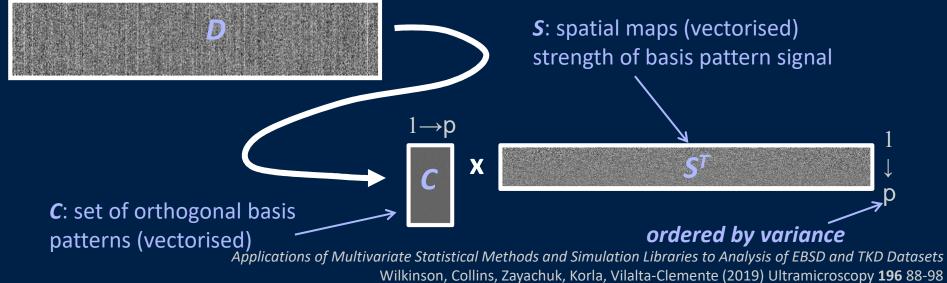




PCA of EBSD/TKD Patterns

Principal Component Analysis

$$\boldsymbol{D}_{[m \times n, s \times t]} = \boldsymbol{C}_{[m \times n, p \leq m \times n]} \boldsymbol{S}_{[p \leq m \times n, s \times t]}^{T}$$



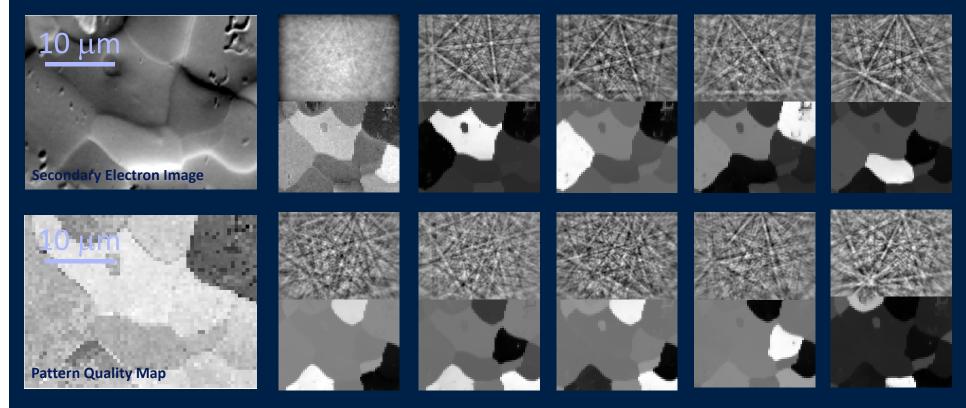
Wilkinson, Collins, Zayachuk, Korla, Vilalta-Clemente (2019) Ultramicroscopy 196 88-98



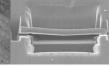




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PCA – Example: Ferritic Steel



Problem!

Components contain multiple overlapping patterns – some with inverted contrast.

Grains have significant signal associated with multiple components. Actually want a single component dominating for each grain (ie we want the spatial maps to be close to zeros for all but one component – some times called simplicity)



Varimax Basis Vectors

Principal Component Analysis: $m{D}_{[ext{m} imes ext{n}, ext{s} imes ext{t}]} = m{c}_{[ext{m} imes ext{n}, ext{p} ext{s} imes ext{m}} m{S}_{[ext{p} ext{s} ext{m} imes ext{n}, ext{s} imes ext{t}]}^T$

- Apply (hyper-) rotation to basis vectors
- the 'Varimax' rotation transforms the basis vectors so that each observation (ie EBSD map point) tends to be dominated by a single basis vector (ie pattern).

$$\boldsymbol{D}_{[m \times n, s \times t]} = \boldsymbol{C}_{[m \times n, p \leq m \times n]} \boldsymbol{R}_{[p,p]} \boldsymbol{R}_{[p,p]}^T \boldsymbol{S}_{[p \leq m \times n, s \times t]}^T$$
Patterns

Maps

• **R** maximizes the sum of squared correlations between variables and factors

$$R_{ ext{VARIMAX}} = rg \max_R \left(rac{1}{p} \sum_{j=1}^k \sum_{i=1}^p (\Lambda R)_{ij}^4 - \sum_{j=1}^k \left(rac{1}{p} \sum_{i=1}^p (\Lambda R)_{ij}^2
ight)^2
ight)$$

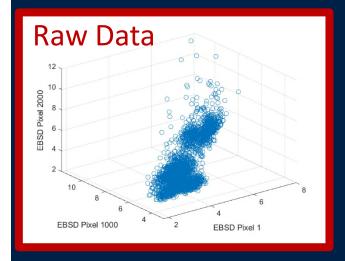
Applications of Multivariate Statistical Methods and Simulation Libraries to Analysis of EBSD and TKD Datasets
Wilkinson, Collins, Zayachuk, Korla, Vilalta-Clemente (2019) Ultramicroscopy **196** 88-98

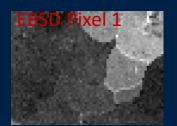


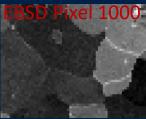


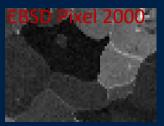


PCA of EBSD Data









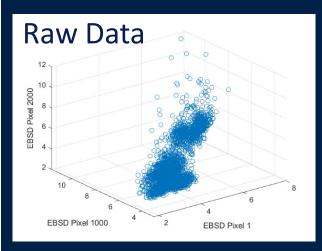


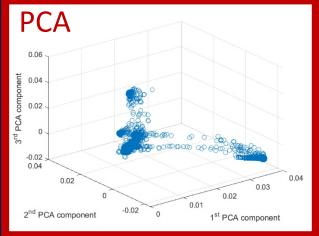






PCA of EBSD Data



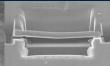








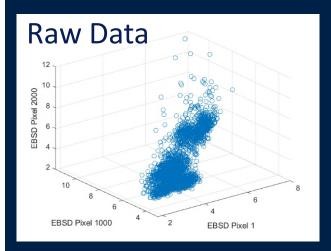


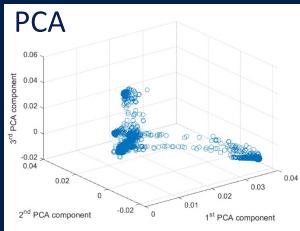


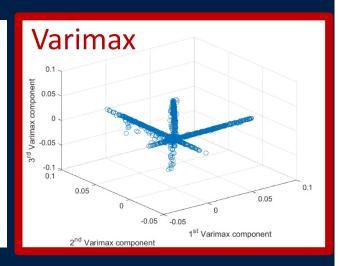




PCA of EBSD Data













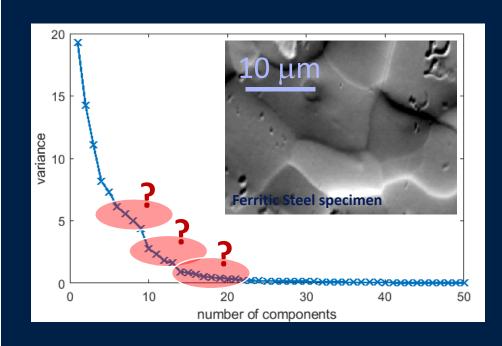
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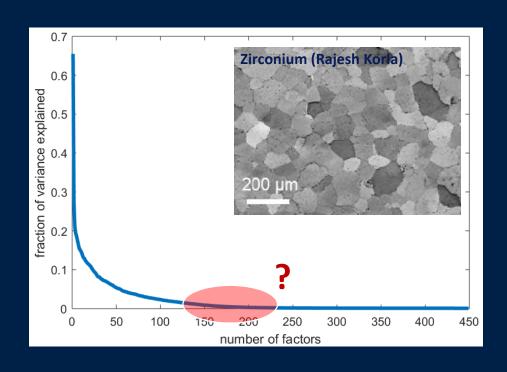
Varimax – Example: Ferritic Steel 20 **Secondary Electron Image Pattern Quality Map fordMicromechanics UNIVERSITY OF** OXFORD



Scree plot

- plot variance associated with successive components
- 'elbow' shows transition from signal to noise
- but
 - Subjective
 - Multiple elbows
 - Smooth transition

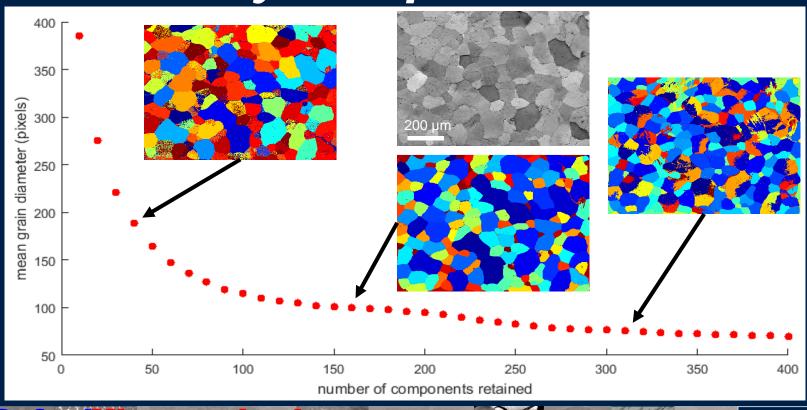




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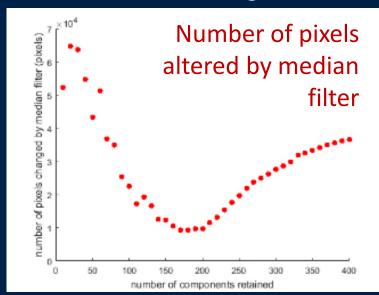


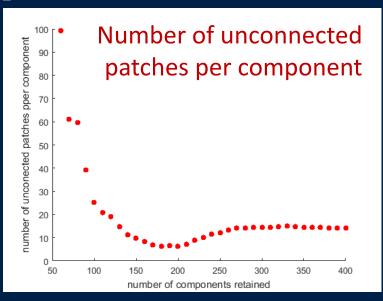


xfordMicromechanic









- Use more specific measures reflecting expected form of grain structure
- Aim to allow more components than stitch back together through indexing



Characteristic Patterns

- Enhanced signal to noise for characteristic patterns (important for specimens that are difficult to prepare or suffer beam damage...). 'Smart averaging' over similar microstructural domains identified direct from data.
- Subtle effects can be discriminated (eg polarity)
- Reduced pattern numbers for indexing
 - Hough-based → try AstroEBSD
 - Template matching → significant reduction of computational time (stay tuned for next talk from Katharina Marquardt)



